

膜厚計 Elli-RI

## 太陽電池対応膜厚計 MODEL: Elli-RI

**新製品**



### 特徴

- 光源にハロゲンを使用
- Textured対応
- 非接触測定
- 測定時間が早い
- コンパクト
- 簡単操作
- 価格が安い

サンプルデモを受け付けしております。

国際特許申請中



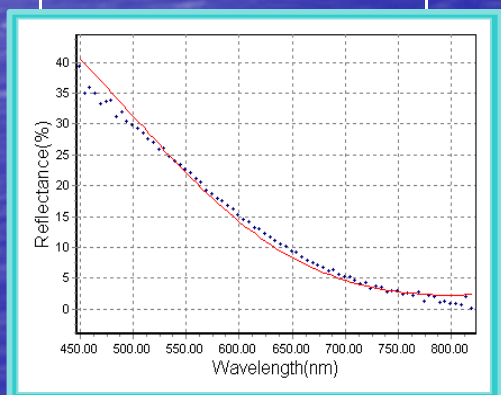
# 太陽電池対応膜厚計 EII-RI

INFORMATION	LAYER	Back side
Sample #1	Baby blue	Poly
Sample #2	Normal blue	Poly
Sample #3	Dark blue	textured

Sample #1



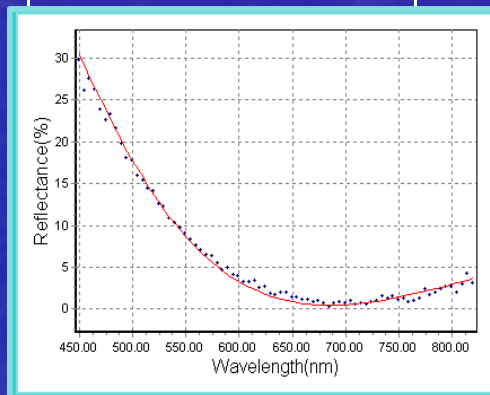
Thickness : 89.88nm  
N : 2.250 k : 0



Sample #2



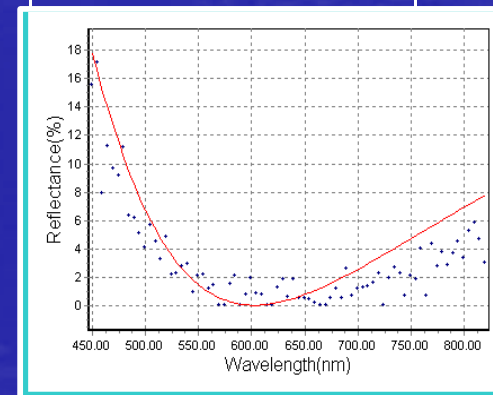
Thickness : 82.22nm  
N : 2.0925 k : 0



Sample #3



Thickness : 74.95nm  
N : 2.002 k : 0





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## PERFORMANCE

Throughput : 1.0 sec. per point (depends on film type)  
Measuring constants : Reflectivity, Film thickness,  $n$ ,  $k$  vs  $\lambda$   
Number of layers : Up to 3 layers (depends on film type)  
Repeatability ( $3\sigma$ ) :  $\pm 0.3$  nm on 10 times measurement  
(depends on film type)  
Thickness range : 10 nm  $\sim$  50  $\mu$ m (depends on film type)

## REFLECTOMETER SYSTEM

Light source : 150 W Halogen Lamp  
Spot size : 4 mm  
Optic system : Collimating optics system, fiber guided optics  
Spectral range : 400 – 900 nm  
Spectrograph : CCD type

## APPLICATION

### Solar Cell

- Textured Mono- and/or Multi- crystalline Substrates
- Antireflective Coating(ARC) on Textured Silicon Solar Cell (SiNx, AlNx...)
- Transparent Conductive Oxides (ITO, ZnOx, doped SnO2, AZO)
- a-Si,  $\mu$ c-Si, poly-Si
- Organic PV Materials
- Dye Sensitized Films

### Semiconductor

- Si, Ge, SiO2, ONO, ZnO, PR, poly-Si, GaN, GaAs

### Display

- (incl. OLED) MgO, ITO, PR, Alq3, CuPc, PVK, PAF, PEDT-PSS

### Dielectrics

- SiO2, TiO3, Ta2O5, ITO, AlN, ZrO2, Si3N4, Ga2O3, Wet Oxides

### Polymer

- Dye, NPB, MNA, PVA, PET, TAC, PR

### Chemistry

- Organic Film(OLED) & LB Thin Film